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Synthesis and characterization of Cr⁴⁺-doped Ca₂GeO₄ tunable crystal



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ABSTRACT

The growth, structure and spectral properties of a $Cr^{4+}:Ca_2GeO_4$ single crystal have been reported in this paper. XPS analysis demonstrated that the chromium in the single crystal is tetravalent; this is further confirmed by fluorescence spectroscopy. The near-infrared, visible absorption and near-infrared luminescence spectrum of the $Cr^{4+}:Ca_2GeO_4$ crystal are presented in this paper. In the absorption spectra, the transitions from the ${}^{3}A_2$ ground state to the three orbital components of the ${}^{3}T_1$ and ${}^{3}T_2$ excited state are observed. The range of the fluorescence spectroscopy band of the $Cr^{4+}:Ca_2GeO_4$ crystal at room temperature is from 1000 nm to 1600 nm. The single band with a maximum peak at 1317 nm at room temperature is attributed to the ${}^{3}T_2 \rightarrow {}^{3}A_2$ transition of the Cr^{4+} ions. The FWHM of the fluorescence spectrum is 201.19 nm, and the fluorescence lifetime and emission cross section are up to 12 μ s and ${}^{4.61} \times 10^{-19}$ cm², respectively.

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1. Introduction

Diode pumped passively Q-switched laser produces high peak power and high repetition rate laser light in the nanosecond and sub-nanosecond range, which is characterized by compact structure, economy, and solidification [1,2]. This laser can be widely used in radar, ranging, remote sensing, nonlinear optical processing, and material processing [3–6]. Cr⁴⁺ ions in a crystal show great potential for use in a tunable solid-state laser in the spectral range of 1.1–2 um at room temperature [7]. Cr⁴⁺ ion laser crystal mainly includes Cr⁴⁺:YAG [8,9]. The main absorption bands of the crystals include 0.48 µm, 0.65 µm, and 1 µm. The absorption transition that is excited from ground state ${}^{3}A_{2}$ to state ${}^{3}T_{1}$ results in 0.65 µm absorption band, whereas 1 µm infrared absorption band is the result of absorption transition that is excited from ground state ³A₂ to state ³T₂. Cr⁴⁺:YAG crystal growth, spectroscopic properties, and laser properties were studied [10,11]. Moreover, the research indicated that not only 1.06 µm Nd:YAG is the ideal pump source of Cr⁴⁺:YAG, but also InGaAs high-power diode is the preferred pump source of Cr⁴⁺:YAG lasers, which are toward all-solid state and miniaturization. Cr⁴⁺:YAG crystal have large amounts of

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 Cr^{3+} ions as impurities, leading to low Cr^{4+} concentrations and reducing the figure of merit in the crystal [12,13]. Cr^{4+} :YAG crystal requires a charge-compensating codopant during crystal growth process. In addition, the nonradiative relaxation of the laser level is significant in Cr^{4+} :YAG crystals. Moreover, the fluorescencequenching effect of Cr^{4+} :Ca₂GeO₄ is significantly less than that of Cr^{4+} :Ca₂GeO₄ at room temperature. Therefore, Cr^{4+} :Ca₂GeO₄ crystal is a promising near-infrared laser material. Researchers state that these crystals are ideal optical communication tunable laser crystals. Several wide practical applications, such as in medicine, telecommunication fiber sensing, and semiconductor diodes, have been recently demonstrated for Cr^{4+} :Ca₂GeO₄ crystal [14–18]. In this paper, we present the flux growth and properties of the Cr^{4+} :Ca₂GeO₄ crystal.

2. Experimental details

In this experiment, Cr₂O₃(5N), GeO₂(5N), CaCO₃ (analytical grade) and CaCl₂ (analytical grade) were used as reagents. The Cr⁴⁺:Ca₂GeO₄ crystal was grown by the flux growth method from the flux of CaCl₂ with a Ca₂GeO₄ concentration of 65 wt.% and a Cr₂O₃ concentration of 0.5 wt.%. The crystallization parameters were as follows: growth direction is [100]; the platinum wire seeding temperature range was 700–1000 °C; the pulling rate was 0.1–0.2 mm/h; the seed rotation speed was 20–60 rpm; the growth atmosphere was oxygen. Finally, the fully transparent, dark-green Cr4+:Ca₂GeO₄ crystals with more than \emptyset 15 mm × 60 mm were been grown under the growth conditions. In this experiment, the GeO₂ content was in excess by 5–8% to account for the volatility of GeO₂ at the high temperatures used. The crystal image is shown in Fig. 1.

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Fig. 1. Image of Cr⁴⁺:Ca₂GeO₄ crystal.

3. Results and discussion

3.1. The formation mechanism of the Cr^{4+} ion

In the case of a $Cr^{4+}:Ca_2GeO_4$ crystal grown by the flux method, the Cr^{4+} ion was obtained by oxidizing of Cr^{3+} from Cr_2O_3 in the oxygen atmosphere with the Ca element added to the melt as a charge compensator. The roles of Ca and O₂ are explained using the following chemical reaction [19]:

$$4Cr^{3+} + 2\left(V_0^{2+} + 2Ca^{2+}\right) + O_2 \rightarrow 4Cr^{4+} + 4Ca^{2+}$$

where V_0^{2+} indicates the oxygen vacancy in the crystal.

The powder X-ray diffraction results for the 0.5 wt.% Cr^{4+} : Ca_2GeO_4 single crystal are shown in Fig. 2. A single phase of the Ca_2GeO_4 with no additional peaks indicates that Cr^{4+} has been successfully incorporated in the crystal by the flux method. The result is in accordance with the standard JCPDS card (No. 26-0304). According to the JCPDS26-0304 card, the crystal structure can be indexed as an olivine-type structure. According to the diffraction formula:

$$2d\sin(\theta) = n\lambda \tag{1}$$

When *n* = 1, this formula can be written as follows: $d = \lambda/2 \sin(\theta)$.



Fig. 2. XRD curve of the 0.5 wt.% Cr⁴⁺:Ca₂GeO₄ crystal.

The lattice constants of the Cr^{4+} : Ca_2GeO_4 crystal can be obtained by the following calculation formula of the tetragonal system.

$$d = \frac{abc}{\sqrt{\ell^2 a^2 b^2 + h^2 b^2 c^2 + k^2 a^2 c^2}} \dots \dots$$
(2)

d values can be obtained with Formula (1). We selected four different crystal plane (*hkl*) values, such as (111), (121), (200) and (002), and then we placed the corresponding *d* values into Formula (2) to produce four equations. The lattice constant has been obtained by solving equations with *a* = 5.3209 Å, *b* = 6.6648 Å, and *c* = 11.2606 Å. The results are very similar to those of the pure Ca₂GeO₄ phase. The lattice distortion caused by Cr⁴⁺ ions is quite small because the radii of the Cr⁴⁺ and Ge⁴⁺ are very similar.

3.2. Raman spectra

The Raman spectra of the Ca_2GeO_4 single crystal are shown in Fig. 3. The two strongest lines at 736 and 760 cm⁻¹ in the Ca_2GeO_4 crystal are attributed to the $(GeO_4)^{4-}$ tetrahedral v3 and v1 stretching modes. The weak Raman peaks at 428 and 680 cm⁻¹ are similar to those peaks that were reported in literature [20].

3.3. XPS analysis of the Cr⁴⁺:Ca₂GeO₄ crystal

Fig. 4 shows the XPS survey spectra of the 0.5 wt.% Cr^{4+} :Ca₂GeO₄ crystal. Fig. 4 demonstrates that the Cr^{4+} :Ca₂GeO₄ crystal has Cr, Ca, Ge, O and C elements, where the C element is not an inherent component in the crystal. Information about the hydrogen element cannot be obtained from photoelectron spectroscopy, Thus, Cr^{4+} :Ca₂GeO₄ crystal may have an H-element.

The atomic concentrations of major elements and the peak banding energy of the elements in the crystal are shown in Table 1. The table dose not present the content of Cr element because the Cr^{4+} ion content in this crystal is less than the lowest measured value limits (0.1 mol%) used in the photoelectron spectroscopy, the content of the Cr element cannot be detected because of two main reasons. the sensitivity of the apparatus is low, the segregation coefficient of Cr element is small, which results in the low actual concentration of Cr^{4+} ions in this crystal.

In addition, the ratio of the main elements Ca:Ge:O is 1.98:1:4.15 in the crystal sample, but the ratio is 2:1:4 in Ca₂GeO₄ crystal. This difference is caused by impurities in the Ca, Ge, and O



Fig. 3. Raman spectra of the Cr⁴⁺:Ca₂GeO₄ polycrystallines.

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